

•General Description

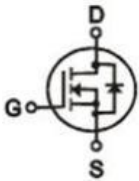
The SGT MOSFET LHL40N100 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is suitable for fast charge and lighting.

•Features

- Fast switching
- Low $R_{DS(on)}$ & FOM

•Application

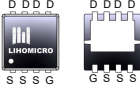
- LED/LCD/PDP TV and monitor Lighting
- Power Supplies



$V_{DS} = 100V$

$R_{DS(ON)} = 14m\Omega$

$I_D = 40A$



pin 1

DFN3*3

■ RoHS COMPLIANT

•Ordering Information:

Part Number	LHL40N100
Package	DFN3*3
Basic Ordering Unit (pcs)	5000
Normal Package Material Ordering Code	LHL40N100D3-DFN3*3-TAP
Halogen Free Ordering Code	LHL40N100D3-DFN3*3-TAP-HF

•Absolute Maximum Ratings (TC =25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current , $T_C = 25^\circ C$	I_D	40	A
Pulsed drain current ($T_C = 25^\circ C$, t_p limited by T_{jmax}) ¹	I_D pulse	120	A
Single Pulse Avalanche Energy ⁴	E_{AS}	30	mJ
Power Dissipation($T_C=25^\circ C$) ²	P_D	72	W
Operating Temperature	T_J	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	°C

●Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	100	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	--	2.5	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS}=10V, I_D=20A$	--	14	18	mΩ
		$V_{GS}=4.5V, I_D=15A$	--	19	24	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=100V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	μA
		$V_{DS}=80V, V_{GS}=0V, T_J=85^\circ C$	--	--	10	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	±100	nA
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=50V, f=1.0MHz$	--	1191	--	pF
Output Capacitance	C_{oss}		--	195	--	
Reverse transfer Capacitance	C_{rss}		--	4.1	--	
Turn-On Delay time	$T_d(on)$	$V_{GS}=10V, V_{DS}=50V, R_G=2.2\Omega, I_D=10A$	--	17.8	--	nS
Turn -Off Delay Time	$T_d(off)$		--	33.5	--	
Turn-On Rise time	T_r		--	3.9	--	
Turn-Off Fall time	T_f		--	3.2	--	
Total Gate Charge	Q_g	$I_D=10A, V_{DS}=50V, V_{GS}=10V$	--	20	---	nC
Gate-to-Source Charge	Q_{gs}		--	2.4	--	
Gate-to-Drain Charge	Q_{gd}		--	5.3	---	
Continuous Diode Forward Current	I_S	--	--	--	40	A
Pulsed Diode Forward Current	I_{SM}	--	--	--	120	A
Diode Forward Voltage	V_{SD}	$T_J=25^\circ C, I_S=8A, V_{GS}=0V$	--	--	1.3	V
Reverse Recovery Time	T_{rr}	$I_S=8A, di/dt=100A/\mu S$	--	51	--	nS
Reverse Recovery Charge	Q_{rr}		--	95	--	nC
Peak Reverse Recovery Current	I_{rrm}		--	2.5	--	A

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	1.72	°C/W
Thermal Resistance Junction-ambient ³	R_{thJA}	62	°C/W

Notes:

1.Repetitive Rating: Pulse width limited by maximum junction temperature.

2.Pd is based on max. junction temperature,using junction-case thermal resistance.

3.The value of R_{thJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz copper,in a Still air environment with $T_a=25^\circ C$.

4. $V_{DD}=50V, R_G=25\Omega$, Starting $T_J=25^\circ C$.

•Typical Characteristics

Figure 1. Typ. output characteristics

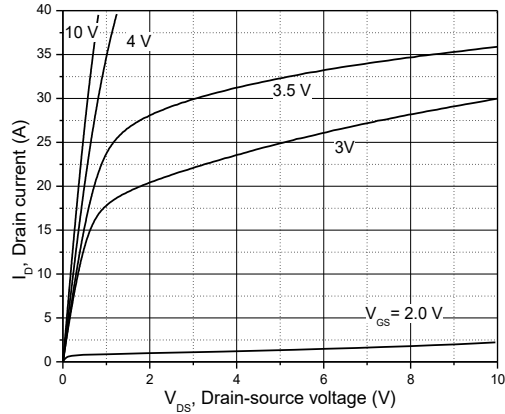


Figure 2. Typ. transfer characteristics

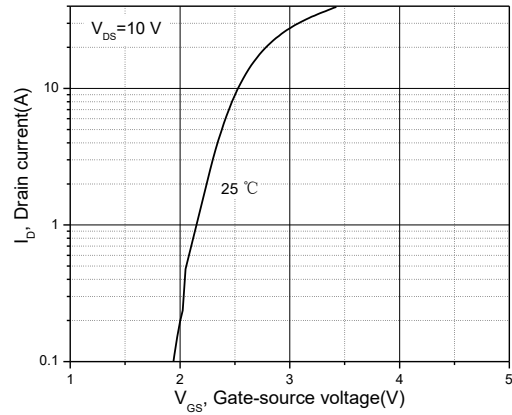


Figure 3. Typ. capacitances

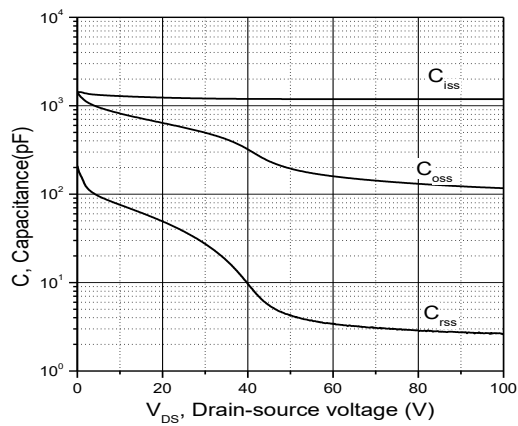


Figure 4. Typ. gate charge

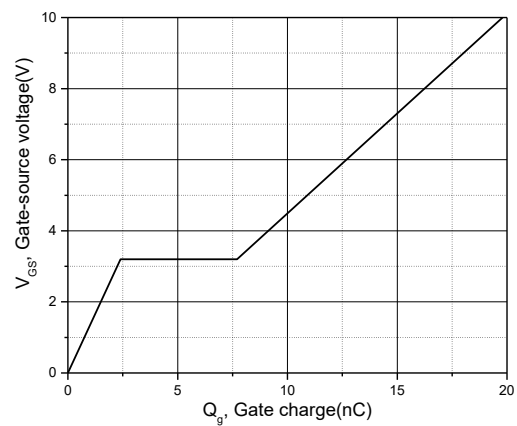


Figure 5. Drain-source breakdown voltage

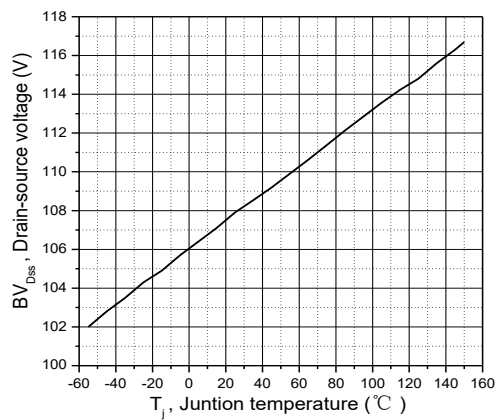
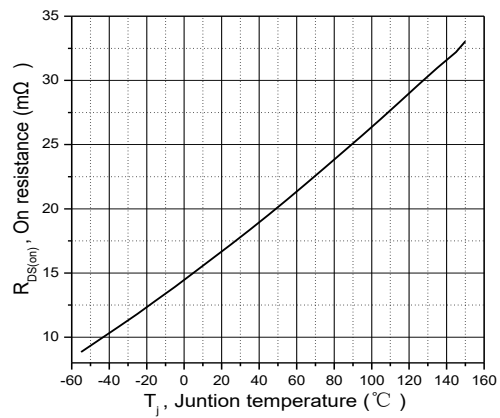


Figure 6. Drain-source on-state resistance



• **Typical Characteristics**(cont.)

Figure 7. Forward characteristic of body diode

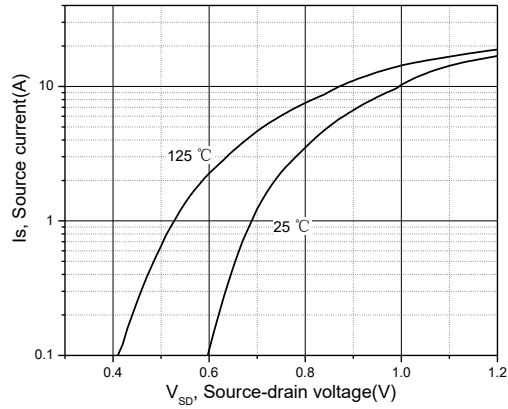


Figure 8. Drain-source on-state resistance

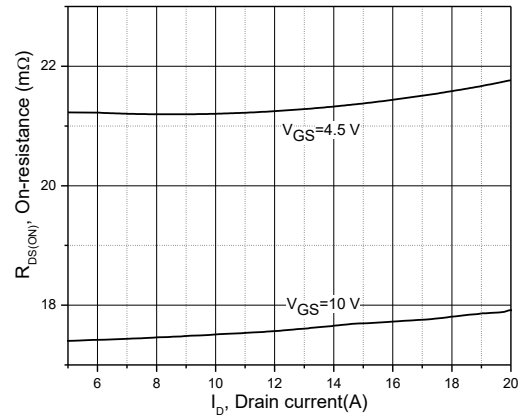
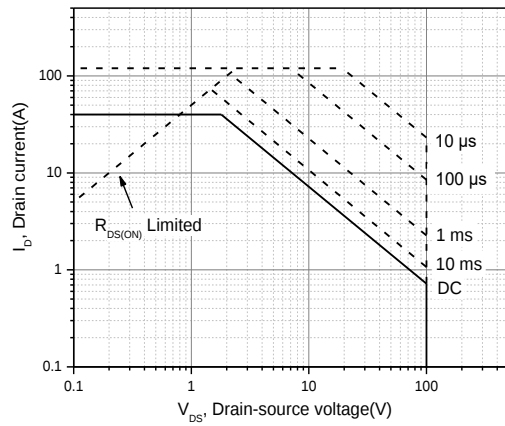


Figure 9. Safe operation area TC=25 °C



• Test Circuits & Waveforms

Figure 1. Gate charge test circuit & waveform

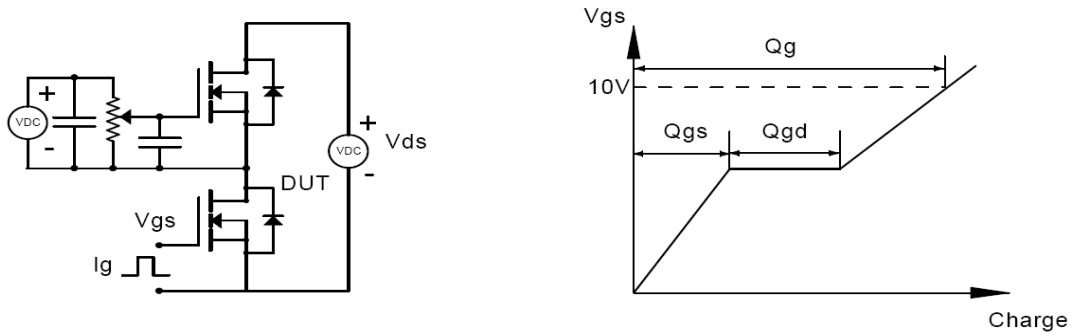


Figure 2. Switching time test circuit & waveforms

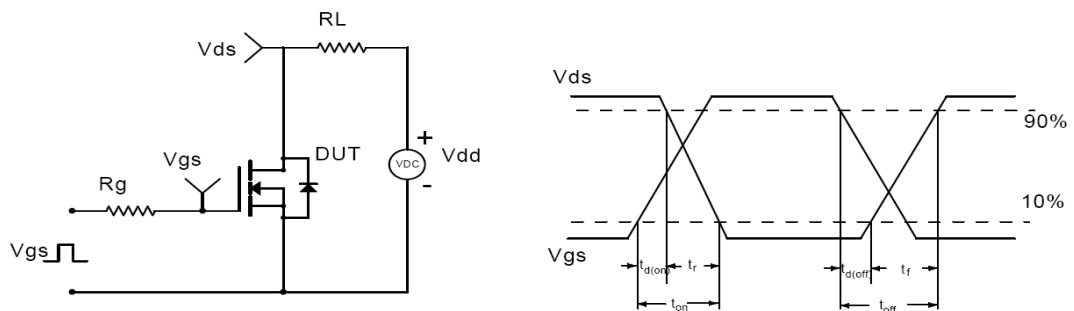


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

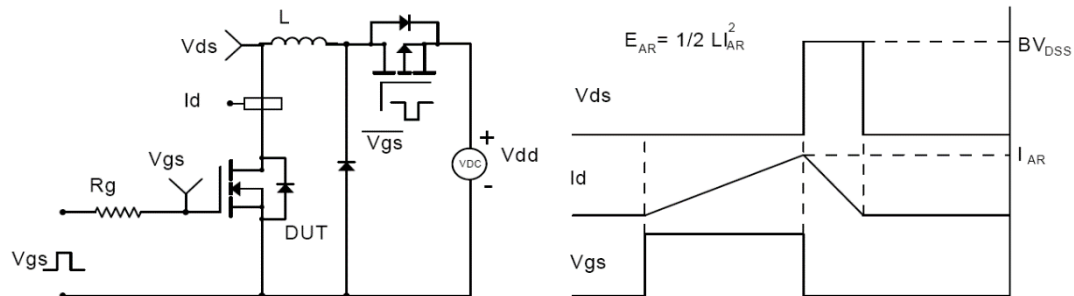
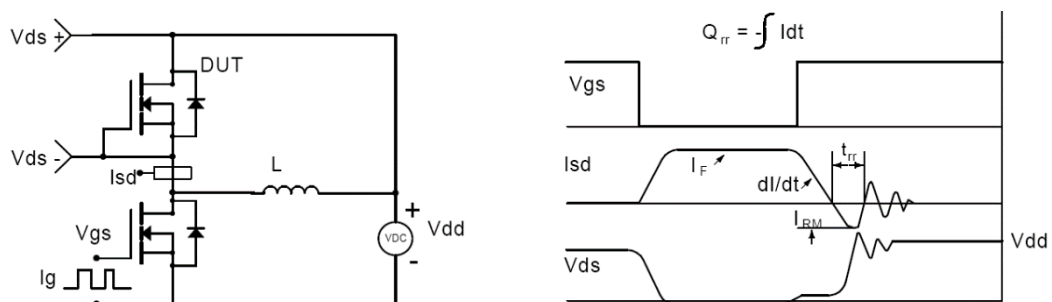


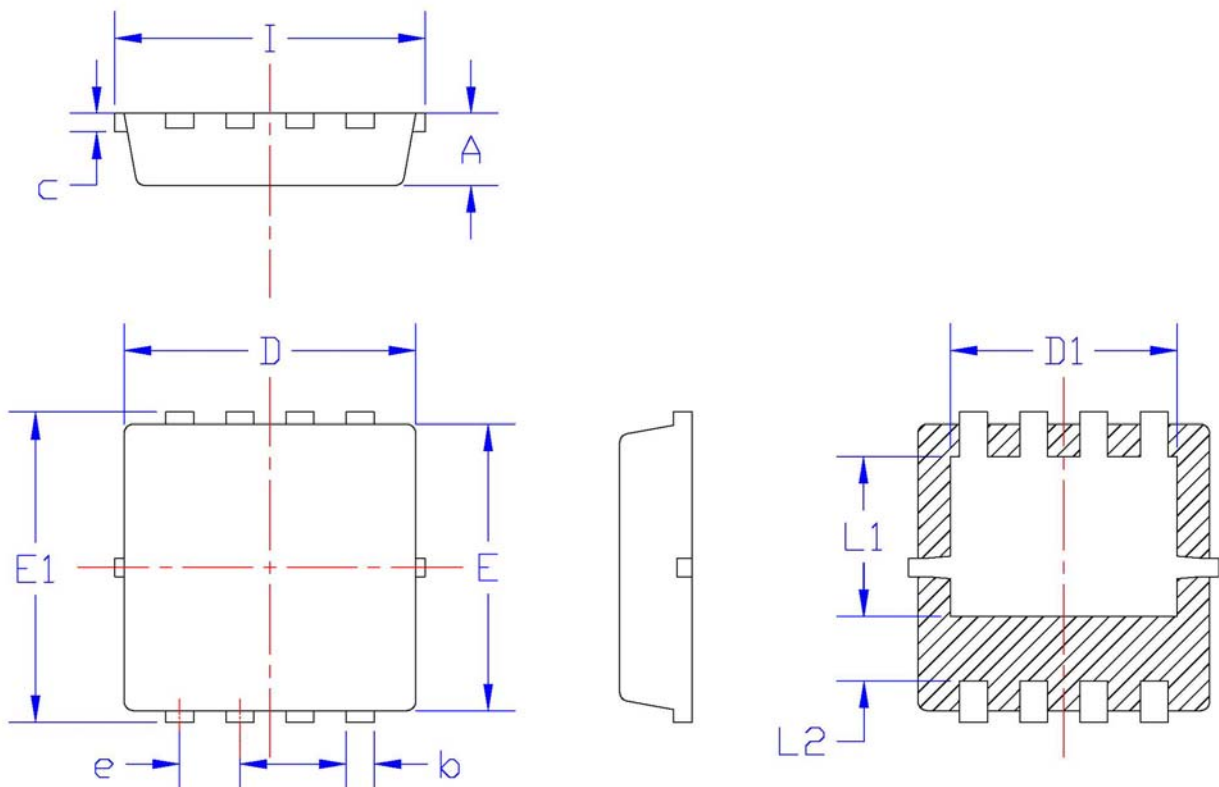
Figure 4. Diode reverse recovery test circuit & waveforms



• Dimensions (DFN3*3)

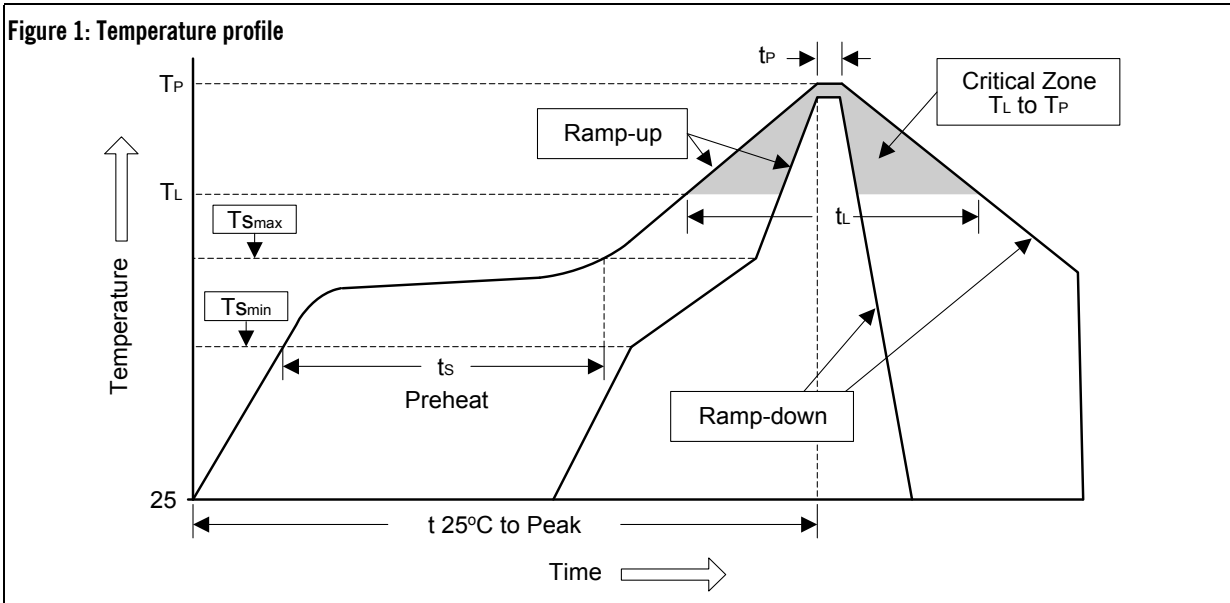
Unit: mm

SYMBOL	min	max	SYMBOL	min	max
A	0.68	0.88	e	0.65BSC	
b	0.27	0.47	L1	1.55	1.95
c	0.15	0.35	L2	0.5	0.9
D	3.05	3.25	I	3.10	3.50
D1	2.25	2.65			
E	3.05	3.25			
E1	3.15	3.55			



• Soldering Methods for Silicongear's Products

1. Storage environment: Temperature=10°C to 35°C Humidity=65%±15%
2. Reflow soldering of surface-mount devices



Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate (T_L to T_P)	<3°C/sec	<3°C/sec
Preheat		
- Temperature Min (T_{Smin})	100°C	150°C
- Temperature Max (T_{Smax})	150°C	200°C
- Time (min to max) (t_s)	60 to 120 sec	60 to 180 sec
T_{Smax} to T_L		
- Ramp-up Rate	<3°C/sec	<3°C/sec
Time maintained above:		
- Temperature (T_L)	183°C	217°C
- Time (t_L)	60 to 150 sec	60 to 150 sec
Peak Temperature (T_P)	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature (t_P)	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<8 minutes

3. Flow (wave) soldering (solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices.	245°C ±5°C	5sec ±1sec
Pb-Free devices.	260°C +0/-5°C	5sec ±1sec